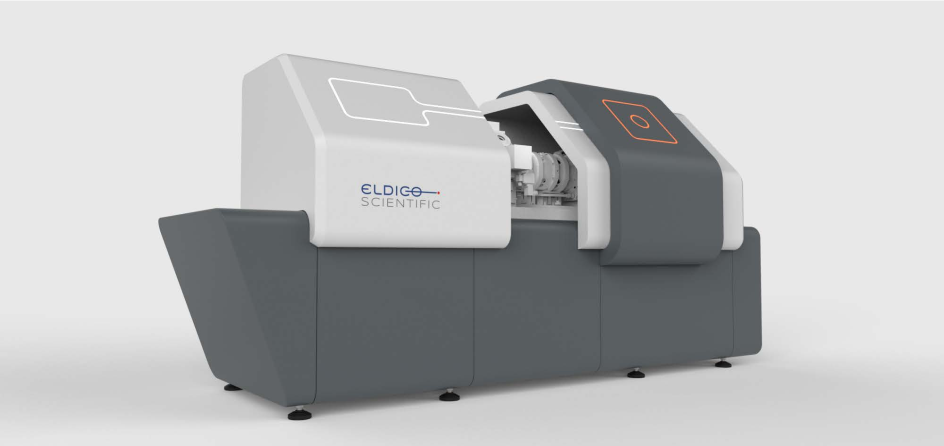
ELDICO *ED-1*

THE ELECTRON DIFFRACTOMETER

Product & Services



Our sales and service system is tailored to the needs of our customers: from device procurement over leasing to measurement-as-a-service arrangement. Moreover, we are more than happy to provide the package that best fits our customers' specific needs, on an individual basis.

System purchase

Our product is a ready-to-install instrument that produces high-quality structural information directly in the nanocrystal regime and delivers reliable results within a few hours, with a clear cost advantage per measurement. Please contact us to learn more about our superior solution.

Subscription & leasing

We offer CAPEX-friendly solutions for the customers who do not want to run the system themselves. By teaming up with experienced partners, we provide our customers neutral subscription solutions, ranging from a basic leasing option to sophisticated performance-based contracts.

Measurement-as-a-service

From diffraction data collection (and pre-processing), structure determination (and refinement) to advanced structural analyses such as determination of the absolute configuration, we offer tailor-made service packages demonstrating good practices, reproducible results and timely delivery.

Measurement-as-a-Service

Part no. 2004: Crystal Structure Determination

Electron Diffraction measurement on a single, stable, solid, crystalline sample of 10 nm minimum dimension in one direction, preferably 200-300 nm in the other directions. Deliverable will be the diffraction data as a normalized intensity file, structure solution and kinematic refinement, molecular structure, crystallographic files (.lst, .res, .ins, .fcf, .cif), and crystallographic tables.

Part no. 2006: Absolute configuration determination

Electron Diffraction Measurement on a single, stable, solid, crystalline sample of 10 nm minimum dimension in one direction, preferably 200-300 nm in the other directions. Deliverable will be the diffraction data as a normalized intensity file, structure solution and absolute configuration determination, including molecule drawing and atom coordinates.

Part no. 2007: Crystal mapping

Identification using Electron Diffraction of the different crystals on a measurement grid. Identifications will be done by measuring the cell parameters of the crystals on the grid. Deliverables will be the cell parameters of all different crystals analyzed.

Part no. 2008: Determination of micro-crystallinity in amorphous solids

Electron Diffraction Measurement on all crystals on the measurement grid to identify if there is local micro-crystallinity present in one of the crystals.

For these or other services, please contact us at my-sample@eldico.ch